



Seagate® IronWolf® 525 SSD

Product Manual

User Capacity	Standard M.2 2280-D2-M Models
500 GB	ZP500NM30002
1000 GB	ZP1000NM30002
2000 GB	ZP2000NM30002

Revision History

Version and Date	Description of Changes
Rev B, September 2021	Updated the following:
	■ Section 1, Introduction
	■ Section 2, Specifications
	■ Section 6, Feature Details
Rev A, July 2021	First document release.

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Support

For Internal SSD Support, visit: https://www.seagate.com/support/products/

For Firmware Download and Tools Download for Secure Erase, visit: https://www.seagate.com/support/downloads/

For information regarding online support and services, visit: http://www.seagate.com/contacts/

For information regarding Warranty Support, visit: http://www.seagate.com/support/warranty-and-replacements/

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1. Introduction

The Seagate® IronWolf® 525 SSD is built for NAS, and delivers high endurance, performance and caching speeds of up to 5000MB/s for NVMe-compatible systems. The Seagate IronWolf 525 SSD offers PCle Gen 4 x4 interface with NVMe protocol support in an ultra-small M.2 form factor..

Table 1 The IronWolf 525 SSD Features

Feature	Description		
Capacity (User)	■ 500 GB, 1000 GB, 2000 GB		
Certifications, Eco-Compliance	CE, UL, FCC, BSMI, KCC, Microsoft WHQL,ROHS	VCCI, CB	
Dimensions	 Length, Max (mm/in): 80.15 mm/3.156 in Width, Max (mm/in): 22.15 mm/0.872 in Height, Max (mm/in): 3.58 mm/0.141 in 		
Form Factor	■ M.2 2280-D2-M		
Weight	■ 500 GB 8.0g, 1000 GB 8.5g, 2000 GB: 8.7g	3	
Endurance	Total Bytes Written 500 GB: 700 TB 1000 GB: 1400 TB 2000 GB: 2800 TB	See Section 2.5, Reliability/Endurance.	
Interface Compliance	 NVMe 1.3 PCI Express Base 4.0, PCIe Gen 4 x 4 lane, and backward compatible to PCIe Gen3, Gen 2, and Gen 1 		
NAND	■ 3DTLC		
Operating Systems	 Windows 10 (64 bit) Ubuntu 16.04, 18.04 CentOS 6, 7 		
Performance Random	Read: Up to 760,000 IOPS Write: Up to 700,000 IOPS	Actual performance might vary depending on use conditions and environment. See Section 2.2, Performance.	
Performance Sequential	Read: Up to 5000MB/sWrite: Up to 4400MB/s	Actual performance might vary depending on the capacity, use conditions and environment. See Section 2.2, <i>Performance</i> .	
Power Consumption	 Active Power, Average: <7.6 W Idle Power PS3, Average: <30 mW Low Power L1.2 mode: < 2 mW 	See Section 2.3, Power Consumption.	
Power Management	 Supports ActiveStatePower Management (ASPM) Supports Autonomous Power StateTransition (APST) Supports L1.2 		
Security	■ TCG Pyrite		
Reliability	 End-to-end data path protection MTBF: 1.8 million hours UBER: 1 error in 10¹⁶ bits read 		

Table 1 The IronWolf 525 SSD Features (continued)

Feature	Description		
Shock and Vibration	Shock Non-Operating: 1,500 G, at 0.5 ms Vibration Non-Operating: 1.52 G _{RMS} , (20 to 80 Hz, Frequency)	See Section 2.4, Environmental Conditions.	
Temperature Range	■ Operating: 0°C to 70°C ■ Non-operating: -40°C to 85°C		
Voltage	■ Min = 3.14V±5% ■ Max = 3.47V±5%		
Warranty	Five years, or when the device reaches Host TBW, whichever happens first. Endurance rating valid for SSD Life Remaining > 1%.		

1.1 Reference Documents

In case of conflict between this document and the following reference documents, this document takes precedence.

- PCIe Specifications
 - PCIe PCI Express Electromechanical specification, revision 4.0
 - NVMe Non Volatile Memory Express specification 1.3
 - PCIe CEM PCI Express Card Electromechanical specification, revision 1.1
 - PCI Express M.2 Specification, revision 1.1
- Trusted Computing Group (TCG) Documents
 - Storage Work Group Security Subsystem Class: Opal, Version 2.00
- Seagate Documentation
 - SeaTools™ SSD GUI User Guide Publication Number: 100837824
 - SeaChest for SSD User Guide Publication Number: 100847684

2. Specifications

2.1 Models and Capacity

Table 2 Models and Capacity

User Capacity	Standard M.2 2280-D2-M Models
500 GB	ZP500NM30002
1000 GB	ZP1000NM30002
2000 GB	ZP2000NM30002

NOTE About capacity:

Sector Size: 512 Bytes

User-addressable LBA count = (97696368) + (1953504 x (Desired Capacity in Gb-50.0)) From International Disk Drive Equipment and Materials Association (IDEMA) (LBA1-03_standard.doc)

2.2 Performance

Table 3 FOB Random and Sequential Read and Write Performance (PCIe Gen4 x4)

Parameter	500 GB	1000 GB	2000 GB
Sequential Read (Max, MB/s), 128KB	5000	5000	5000
Sequential Write (Max, MB/s), 128KB	2500	4400	4400
Random Read (Max, IOPS), 4KB QD32 T8	420,000	760,000	740,000
Random Write (Max, IOPS), 4KB QD32 T8	630,000	700,000	700,000

NOTE About Performance:

- Fresh out of box (FOB) performance obtained on newly formatted drive.
 Performance may vary based on the SSD's firmware version, system hardware, and configuration.
- Performance based on Windows 10 host with PCle Gen4 motherboard.
- CrystalDiskMark 8.0.1, 1GB range, QD=32, Thread=1, 1GB range, QD=32, Thread=8 (random)
- Sequential Read/Write is measured while testing 1000 MB five times by CrystalDiskMark.

Table 4 Sustained Random and Sequential Read and Write Performance (PCIe Gen4x4)

Parameter	500 GB	1000 GB	2000 GB
Sequential Read (Max, MB/s), 128KB QD32	3300	4350	4300
Sequential Write (Max, MB/s), 128KB QD32	525	995	965
Random Read (Max, IOPS), 4KB QD256	230,000	445,000	425,000
Random Write (Max, IOPS), 4KB QD256	10,800	19,500	19,500

NOTE

About performance:

- Performance based on host with PCle Gen4 motherboard and Ubuntu 16.04 operating system.
- Performance is measured with the following conditions
 - Sustained Sequential: FIO, full-range, 128K data size, QD=32
 - Sustained Random: FIO, full-range, 4K data size, QD256
- Performance may vary based on the SSD's firmware version, system hardware, and configuration.

Table 5 FOB Random & Sequential, Read & Write Performance (PCIe Gen3 x4)

Parameter	500 GB	1000 GB	2000 GB
Sequential Read (Max, MB/s), 128KB QD32	3400	3400	3400
Sequential Write (MB/s),128KB QD32	2500	3200	3200
Random Read (IOPS), 4KB QD256	420,000	640,000	640,000
Random Write (IOPS), 4KB QD256	10,800	19,500	19,500

NOTE

About performance:

- Fresh out of box (FOB) performance obtained on newly formatted drive. Performance may vary based on SSD's firmware version, system hardware, and configuration.
- Performance based on Windows 10 host with PCle Gen3 motherboard.
- CrystalDiskMark 8.0.1, 1GB range, QD=32, Thread=1, 1GB range, QD=32, Thread=8 (random)
- Sequential Read/Write is measured while testing 1000 MB five times by CrystalDiskMark.

Table 6 Sustained Random and Sequential Read and Write Performance (PCIe Gen3 x4)

Parameter	500 GB	1000 GB	2000 GB
Sequential Read (MB/s),Sustained,128KB QD32	3250	3300	3300
Sequential Write (MB/s) Sustained, 128KB QD32	525	995	965
Random Read (IOPS) Sustained, 4KB QD256	230,000	445,000	425,000
Random Write (IOPS) Sustained, 4KB QD256	10,800	19,500	19,500

NOTE

About performance:

- Performance based on host with PCle Gen3 motherboard and Ubuntu 16.04 operating system.
- Performance is measured with the following conditions:
 - Sustained Sequential: FIO, full-range, 128K data size, QD=32
 - Sustained Random: FIO, full-range, 4K data size, QD=256
- Performance may vary based on the SSD's firmware version, system hardware, and configuration.

2.3 Power Consumption

Table 7 Power Consumption

Parameter	500 GB	1000 GB	2000 GB
Max. Average Read (mW)	6200	7600	7600
Max. Average Write (mW)	5600	6500	6500
Idle PS3 (mW) (APST off)	20	20	30
L1.2 (mW)	2	2	2

NOTE

About power consumption:

- The average value of power consumption is based on 100% conversion efficiency.
- The measured power voltage is 3.3 V.
- Measured under ambient temperature.
- Power Consumption can differ according to flash configuration and platform.
- Power consumption is measured during the sequential read and write (128KB) operations performed by Linux FIO3.7.
- APST means Autonomous Power State Transitions in the NVMe specification.

2.4 Environmental Conditions

Table 8 Temperature, Humidity, Shock

Specification	Value
Temperature	
Operating (case temperature at specific airflow)	0°C to 70°C
Non-operating	-40°C to 85°C
Humidity	
Operating	90%
Non-operating (storage)	93%
Shock	
Non-operating	1,500 G, duration 0.5 ms
Vibration	
Non-operating	1.52 G _{RMS,} (20Hz to 80Hz, Frequency)

NOTE

Temperature is measured without condensation. Operating mode temperature is measured by temperature sensor, SMART Attribute.

Airflow is suggested. Airflow allows the device to be operated at the appropriate temperature for each component during heavy workloads environments.

Shock and vibration results assume that the SSD is mounted securely with the input vibration applied to the SSD mounting. These specifications do not cover connection issues that may result from testing at this level. The measured specification is in root mean square (RMS) form.

- **Non-operating Shock.** The limits of non-operating shock applies to all conditions of handling and transportation. This includes both isolated SSD and integrated SSDs. Shock may be applied in the X, Y, or Z-axis.
- **Non-Operating Vibration.** The limits of non-operating vibration shall apply to all conditions of handling and transportation. This includes both isolated SSD and integrated SSDs. Vibration may be applied in the X, Y, or Z-axis.

2.5 Reliability/Endurance

Table 9 Reliability/Endurance

Specification	Value		
Mean time between failures (MTBF)	1.8 million hours		
Bit Error Rate	1 error in 10 ¹⁶ bits read		
Endurance	Total Bytes Written		
	■ 500 GB: 700 TB		
	■ 1000 GB: 1400 TB		
	■ 2000 GB: 2800 TB		

NOTE About endurance:

- The SSD achieves the specified MTBF in an operational environment that complies with the operational temperature range specified in this manual. Operating temperatures are measured by temperature sensor.
- Endurance rating valid for SSD Life Remaining > 1%.
- Endurance is characterized while running Client JESD219A workload (per JESD218 specification).

3. Mechanical Information

Weight: 8.0 g (500 GB) 8.5 g (1000 GB), 8.7 g (2000 GB)

Height: 3.5 mm±0.08 mm Width: 22 mm±0.15 mm Length: 80 mm±0.15 mm

Figure 1 IronWolf 525 SSD Top Side View

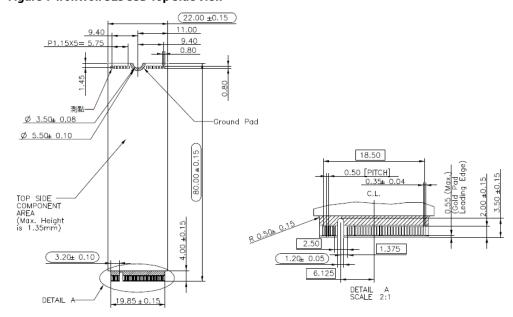


Figure 2 IronWolf 525 SSD Bottom Side View

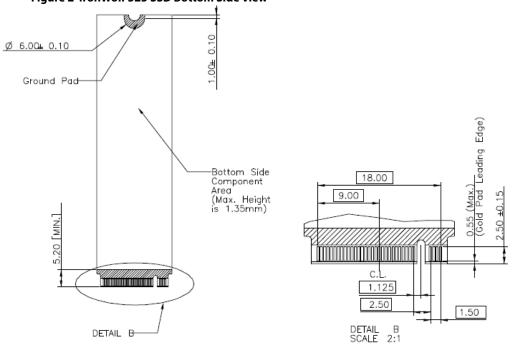
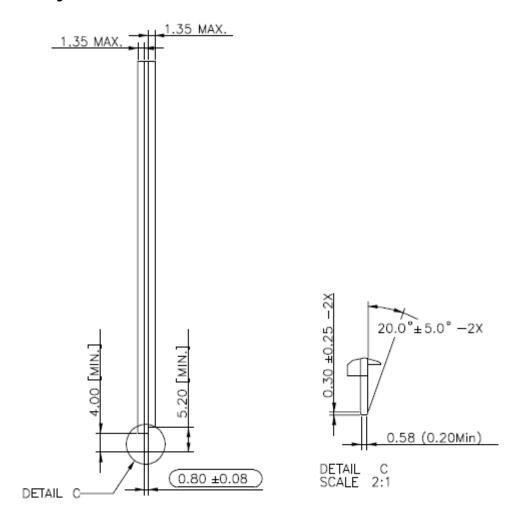


Figure 3 IronWolf 525 SSD Side View



Notes

Notes:

- 1. We = Max Component Height
- 2. = No Component
 3. = No Component / Signal Vias / Signal Copper / Printing
- 4.General Tolerance ±0.15mm
- 5. are critical dimensions

4. Pin and Signal Descriptions

Table 10 Pin Descriptions

Pin No.	PCle Pin	Description	
1	GND	CONFIG_3 = GND	
2	3.3V	3.3V source	
3	GND	Ground	
4	3.3V	3.3V source	
5	PETn3	PCIe TX Differential signal defined by the PCI Express M.2 spec	
6	N/C	No connect	
7	PETp3	PCIe TX Differential signal defined by the PCI Express M.2 spec	
8	N/C	No connect	
9	GND	Ground	
10	LED1#	Open drain, active low signal. These signals are used to allow the add- in card to provide status indicators via LED devices that will be provided by the system.	
11	PERn3	PCIe RX Differential signal defined by the PCI Express M.2 spec	
12	3.3V	3.3V source	
13	PERp3	PCIe RX Differential signal defined by the PCI Express M.2 spec	
14	3.3V	3.3V source	
15	GND	Ground	
16	3.3V	3.3V source	
17	PETn2	PCIe TX Differential signal defined by the PCI Express M.2 spec	
18	3.3V	3.3V source	
19	PETp2	PCIe TX Differential signal defined by the PCI Express M.2 spec	
20	N/C	No connect	
21	GND	Ground	
22	N/C	No connect	
23	PERn2	PCIe RX Differential signal defined by the PCI Express M.2 spec	
24	N/C	No connect	
25	PERp2	PCIe RX Differential signal defined by the PCI Express M.2 spec	
26	N/C	No connect	
27	GND	Ground	
28	N/C	No connect	
29	PETn1	PCIe TX Differential signal defined by the PCI Express M.2 spec	
30	N/C	No connect	

Table 10 Pin Descriptions (continued)

Pin No.	PCle Pin	Description	
31	PETp1	PCIe TX Differential signal defined by the PCI Express M.2 spec	
32	N/C	No connect	
33	GND	Ground	
34	N/C	No connect	
35	PERn1	PCIe RX Differential signal defined by the PCI Express M.2 spec	
36	N/C	No connect	
37	PERp1	PCIe RX Differential signal defined by the PCI Express M.2 spec	
38	N/C	No connect	
39	GND	Ground	
40	SMB_CLK (I/O)(0/1.8V)	SMBus Clock; Open Drain with pull-up on platform	
41	PETn0	PCIe TX Differential signal defined by the PCI Express M.2 spec	
42	SMB_DATA (I/O)(0/1.8V)	SMBus Data; Open Drain with pull-up on platform.	
43	PETp0	PCIe TX Differential signal defined by the PCI Express M.2 spec	
44	ALERT#(O) (0/1.8V)	Alert notification to master; Open Drain with pull-up on platform; Active low.	
45	GND	Ground	
46	N/C	No connect	
47	PERn0	PCIe RX Differential signal defined by the PCI Express M.2 spec	
48	N/C	No connect	
49	PERp0	PCIe RX Differential signal defined by the PCI Express M.2 spec	
50	PERST#(I)(0/3.3V)	PE-Reset is a functional reset to the card as defined by the PCIe Mini CEM specification.	
51	GND	Ground	
52	CLKREQ#(I/O)(0/3.3V)	Clock Request is a reference clock request signal as defined by the PCIe Mini CEM specification; Also used by L1 PM Sub-states.	
53	REFCLKn	PCIe Reference Clock signals (100 MHz) defined by the PCI Express M.2 spec.	
54	PEWAKE#(I/O)(0/3.3V)	PCIe PME Wake. Open Drain with pull up on platform; Active Low.	
55	REFCLKp	PCIe Reference Clock signals (100 MHz) defined by the PCI Express M.2 spec.	
56	Reserved for MFG DATA	Manufacturing Data line. Used for SSD manufacturing only. Not used in normal operation. Pins should be left N/C in platform Socket.	

Table 10 Pin Descriptions (continued)

Pin No.	PCIe Pin	Description			
57	GND	Ground			
58	Reserved for MFG	Manufacturing Clock line. Used for SSD manufacturing only.			
	CLOCK	Not used in normal operation.			
		Pins should be left N/C in platform Socket.			
59	Module Key M				
60	Module Key M				
61	Module Key M				
62	Module Key M	Module Voy			
63	Module Key M	Module Key			
64	Module Key M				
65	Module Key M				
66	Module Key M				
67	N/C	No connect			
68	SUSCLK(32KHz) (I)(0/3.3V)	32.768 kHz clock supply input that is provided by the platform chipset to reduce power and cost for the module.			
69	N/C	PEDET (NC-PCIe)			
70	3.3V	3.3V source			
71	GND	Ground			
72	3.3V	3.3V source			
73	GND	Ground			
74	3.3V	3.3V source			
75	GND	Ground			

5. SMART Support

The IronWolf 525 SSD supports the SMART command set.

5.1 SMART Attributes

The following table lists SMART Attributes and Descriptions.

Table 11 SMART Attributes (Log Identifier 02h)

Bytes Index	Bytes	Description	
[0]	1	Critical Warning	
[2:1]	2	Composite Temperature	
[3]	1	Available Spare	
[4]	1	Available Spare Threshold	
[5]	1	Percentage Used	
[31:6]	26	Reserved	
[47:32]	16	Data Units Read	
[63:48]	16	Data Units Written	
[79:64]	16	Host Read Commands	
[95:80]	16	Host Write Commands	
[111:96]	16	Controller Busy Time	
[127:112]	16	Power Cycles	
[143:128]	16	Power On Hours	
[159:144]	16	Unsafe Shutdowns	
[175:160]	16	Media and Data Integrity Errors	
[191:176]	16	Number of Error Information Log Entries	
[195:192]	4	Warning Composite Temperature Time	
[199:196]	4	Critical Composite Temperature Time	

6. Feature Details

6.1 Flash Management

6.1.1 Error Correction Code (ECC)

Flash memory cells will deteriorate with use, which might generate random bit errors in the stored data. Thus, IronWolf 525 SSD applies the fourth generation LDPC (Low Density Parity Check) of ECC algorithm, which can detect and correct errors that occur during read process, ensure data has been read correctly, as well as protect data from corruption.

6.1.2 Wear Leveling

NAND flash devices can only undergo a limited number of program/erase cycles, and in most cases, the flash media are not used evenly. If some areas get updated more frequently than others, the lifetime of the device would be reduced significantly. Thus, Wear Leveling is applied to extend the lifespan of NAND Flash by evenly distributing write and erase cycles across the media.

Seagate provides advanced Wear Leveling algorithm, which can efficiently spread out the flash usage through the whole flash media area. Moreover, by implementing both dynamic and static Wear Leveling algorithms, the life expectancy of the NAND flash is greatly improved.

6.1.3 Bad Block Management

Bad blocks are blocks that do not function properly or contain more invalid bits causing stored data to become unstable, and their reliability is not guaranteed. Blocks that are identified and marked as bad by the manufacturer are referred to as "Early Bad Blocks". Bad blocks that are developed during the lifespan of the flash are named "Later Bad Blocks". Seagate implements an efficient bad block management algorithm to detect the factory- produced bad blocks and manages bad blocks that appear with use. This practice prevents data being stored into bad blocks and further improves the data reliability.

6.1.4 TRIM

TRIM is a feature which helps improve the read/write performance and speed of solid-state drives (SSD). Unlike hard disk drives (HDD), SSDs are not able to overwrite existing data, so the available space gradually becomes smaller with each use. With the TRIM command, the operating system can inform the SSD which blocks of data are no longer in use and can be removed permanently. Thus, the SSD will perform the erase action, which prevents unused data from occupying blocks all the time. All trimmed blocks will instantly read as zeros regardless of their actual content.

6.1.5 SMART

SMART, an acronym for Self-Monitoring, Analysis and Reporting Technology, is an open standard that allows a hard disk drive to automatically detect its health and report potential failures. When a failure is recorded by SMART, users can choose to replace the drive to prevent unexpected outage or data loss. Moreover, SMART can inform users of impending failures while there is still time to perform proactive actions, such as copy data to another device.

6.1.6 Over Provisioning

Over Provisioning refers to the inclusion of extra NAND capacity in a SSD, which is not visible and cannot be used by users. With Over Provisioning, the performance and IOPS (Input/output Operations per Second) are improved by providing the controller additional space to manage P/E cycles, which enhances the reliability and endurance as well. Moreover, the write amplification of the SSD becomes lower when the controller writes data to the flash.

6.1.7 Firmware Upgrade

Firmware can be considered as a set of instructions on how the device communicates with the host. Firmware will be upgraded when new features are added, compatibility issues are fixed, or read/write performance gets improved.

6.1.8 Thermal Throttling

The purpose of thermal throttling is to prevent any components in a SSD from over-heating during read and write operations. The device is designed with an on-die and an on-board thermal sensor, and with its accuracy, firmware can apply different levels of throttling to achieve the purpose of protection efficiently and proactively via SMART reading.

Table 12 Current version: Thermal Throttling 2.0

Item	Content			
Smart reporting temperature	Flash normalized case temperature			
Reference of temp. reading	On-board thermal sensor, Controller on-die thermal sensor			
tmt1 threshold	82°C per Smart reported			
tmt2 threshold	85°C per Smart reported			
Protect threshold	95°C per Smart reported			
Protect controller threshold	110°C from on-die thermal sensor			
Fatal threshold	120°C from on-die thermal sensor			
Resume performance threshold	78°C per Smart reported			
Temperature polling frequency	Every 1 sec			
TMT1_state impact	-10% CE			
TMT2_state impact	-20% CE			

NOTE

For optimal performance:

- Provide sufficient airflow and cooling.
- Use a motherboard-integrated heat sink and cooling system.

6.2 Advanced Device Security Features

6.2.1 NVMe format

Secure Erase is a standard NVMe format command and it writes all "0xFF" to fully wipe all the data on the SSDs. When this command is issued, the SSD controller erases its storage blocks and returns the drive to its factory default settings.

6.2.2 Physical Presence SID (PSID)

The Physical Presence SID (PSID) is defined by TCG Pyrite as a 32-character string and its purpose is to revert the SSD back to its manufacturing setting when the drive is set via TCG Pyrite (non-SED). The PSID code is printed on the SSD's label. All user data will be erased when reverting the drive back to manufacturing settings.

6.2.3 Manufacturer's Secure ID (MSID)

The Manufacturer's Secure ID (MSID) is defined by TCG Pyrite as a 32-character string and is assigned during the manufacturing process, which is a password that cannot be changed by the host system. MSID can be obtained electronically from the drive across the interface. On acquiring the SSD, the user must set a new password. If a new password is not set the SSD might be potentially taken control by anyone who can reset the MSID. Such an attack on the drive is known as Denial of Service (DoS) since the rightful owner has been locked out.

6.2.4 Sanitize Operation

The Sanitize feature is an alternative to the existing secure erase capabilities through the Format NVM command and makes a robust data security by ensuring the user data from the drive's media, caches and the Controller Memory Buffer are all wiped by the block erase operations, overwriting or destroying the encryption key. The following table illustrates the types of Sanitize Operations supported.

Table 13 Supported Sanitize Operations

	Sanitize Operation			TCG Commands	
Drive Security Type	Overwrite	Block Erase	Crypto Erase	PSID Revert Process	Instant Security Erase
Non-SED (TCG Pyrite)	Yes	Yes	No	Yes	No

NOTE

Sanitize Overwrite command completion takes at least one hour per terabyte per pass. The number of passes is drive-selectable. The NVMe spec default is 16 passes. Contact Seagate Support for more detailed information.

6.3 SSD Lifetime Management

6.3.1 Total Bytes Written (TBW)

TBW (total bytes written) is a measurement of the SSDs' expected lifespan, which represents the amount of data written to the device. To calculate the TBW of a SSD, the following equation is applied:

 $TBW = [(NAND Endurance) \times (SSD Capacity)] / WAF$

NAND Endurance: NAND endurance refers to the P/E (Program/Erase) cycle of a NAND flash. SSD Capacity: The SSD capacity is the specific capacity in total of a SSD.

WAF: Write Amplification Factor (WAF) is a numerical value representing the ratio between the amount of data that a SSD controller needs to write and the amount of data that the host's flash controller writes. A better WAF, which is near 1, guarantees better endurance and lower frequency of data written to flash memory.

6.3.2 Media Wear Indicator

Actual life indicator reported by SMART Attribute byte index [5], Percentage Used, recommends User to replace drive when reaching to 100%.

6.3.3 Read Only Mode (End of Life)

When drive is aged by cumulated program/erase cycles, media worn- out may cause increasing numbers of later bad block. When the number of available spare is less the threshold(5%, SMART attribute log ID 02h Byte4), the drive will notify Host through AER event and Critical Warning to enter Read Only Mode to prevent further data corruption. User should start to replace the drive with another one immediately.

6.4 An Adaptive Approach to Performance Tuning

6.4.1 Throughput

Based on the available space of the disk, the drive will regulate the read/write speed and manage the performance of throughput. When there still remains a lot of space, the firmware will continuously perform read/write action. There is still no need to implement garbage collection to allocate and release memory, which will accelerate the read/write processing to improve the performance. Contrarily, when the space is being used up, the drive will slow down the read/write processing, and implement garbage collection to release memory. Hence, read/write performance will become slower.

6.4.2 Predict & Fetch

Normally, when the Host tries to read data from the PCle SSD, the PCle SSD will only perform one read action after receiving one command. However, the drive applies Predict & Fetch to improve the read speed. When the host issues sequential read commands to the PCle SSD, the PCle SSD will automatically expect that the following will also be read commands. Thus, before receiving the next command, flash has already prepared the data. Accordingly, this accelerates the data processing time, and the host does not need to wait so long to receive data.

6.4.3 SLC Caching

The firmware design of the device currently adopts dynamic caching to deliver better performance for better endurance and consumer user experience. The SLC caching size is up to 1/3 of free capacity of the SSD.

7. Safety, Standards, and Compliance

Each Hard Drive and Solid State Drive ("device") has a product label that includes certifications that apply to that specific drive. The following information provides an overview of requirements that may apply to the drive.

NOTE

The most up to date information on Safety, Standards, and Compliance for this product is available in the Seagate HDD and SSD Regulatory Compliance and Safety document. You can find this document on the Seagate Support page (Scroll down to the Compliance section.):

https://www.seagate.com/support/products/

7.1 Regulatory Model Numbers

The following regulatory model number represents all features and configurations in the series:

■ STA020



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